

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory		User Part Number PCMF2USB30 Part Description													
											NXP ICN8	Protection IND	OI		
									Assembly reliability labs		WLCSP package				
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects									
	TEST														
	Pre- and Post-Stress														
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below									
		MIL-STD-750-1													
	HTRB	M1038 Method A													
		Tj = Tjmax, Vr = 100% of max. datasheet													
# 5	Bias	reverse voltage	1000 hours	68	4040	0									
	TC	JESD22-A104													
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	24	1440	0									
	UHAST	JESD22-A118													
# 8 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %													
# 8 <b>or</b>	Official Control		96 hours	n.a.	n.a.	n.a.									
		JESD22-A102													
	AC	Tamb = 121 °C, RH = 100 %													
# 8a	Autoclave	Pressure = 205 kPa (29.7 psia)													
	HAST	JESD22-A110													
	Highly Accelerated Stress	Tamb = 130 °C, RH = 85%, VR = 80 % of													
# 9	Test	rated reverse voltage <sup>[1]</sup>	1000 hours	24	1440	0									
# 9	1630		1000 nours	24	1440	U									
	IOL	MIL-STD-750 Method 1037													
		ton = toff, devices powered to insure $\Delta Tj$ =													
# 10	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.									
	RSH	JESD22-A111													
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s		n 2	2.2									
# 20	SD	200 0 = 3 0	10.5	n.a.	n.a.	n.a.									
# 21	Solderability	J-STD-002			n 2	2.2									
# ZI	Solderability		=	n.a.	n.a.	n.a.									

<sup>[1]</sup>The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
NXP ICN8	Protection INDI	4040	0	1,1	9,51E+08

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